

RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 14:08

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

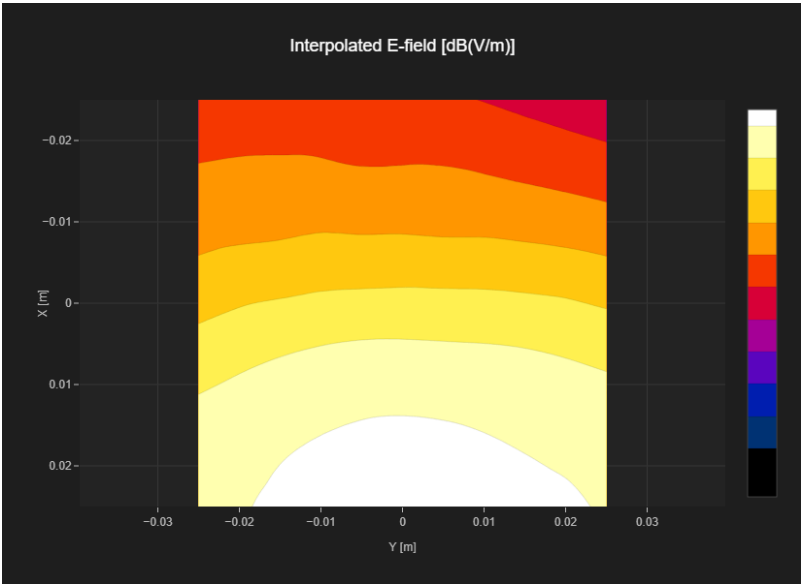
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	128	824.2

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.19	19.48	3.63	23.11



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 14:13

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

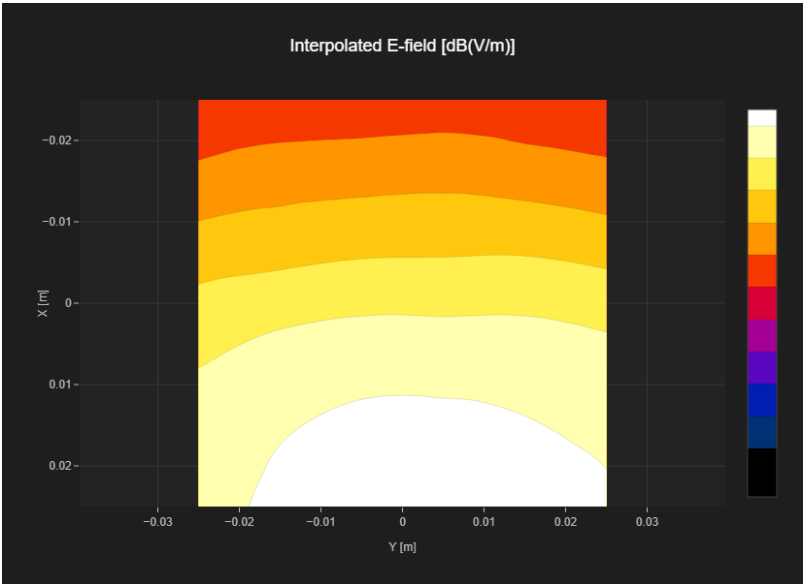
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	190	836.6

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
24.01	20.89	3.63	24.52



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 14:22

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

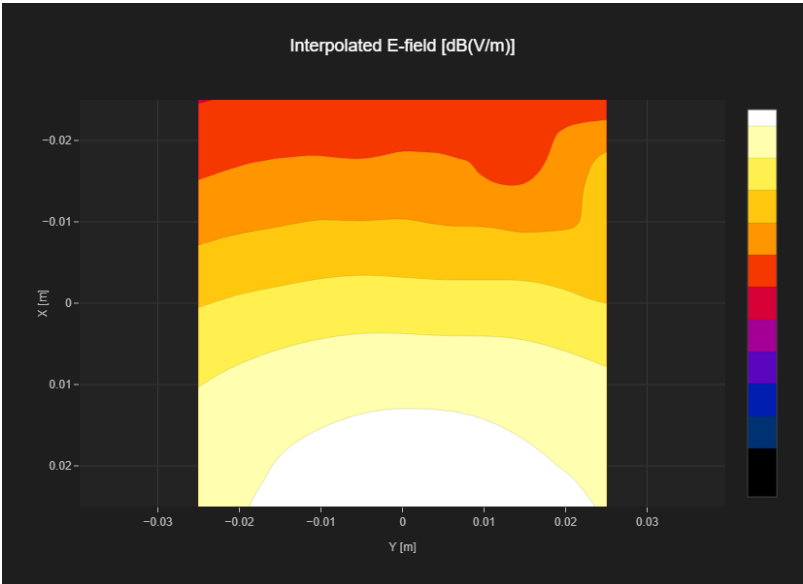
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	251	848.8

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.81	20.33	3.63	23.96



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 14:35

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

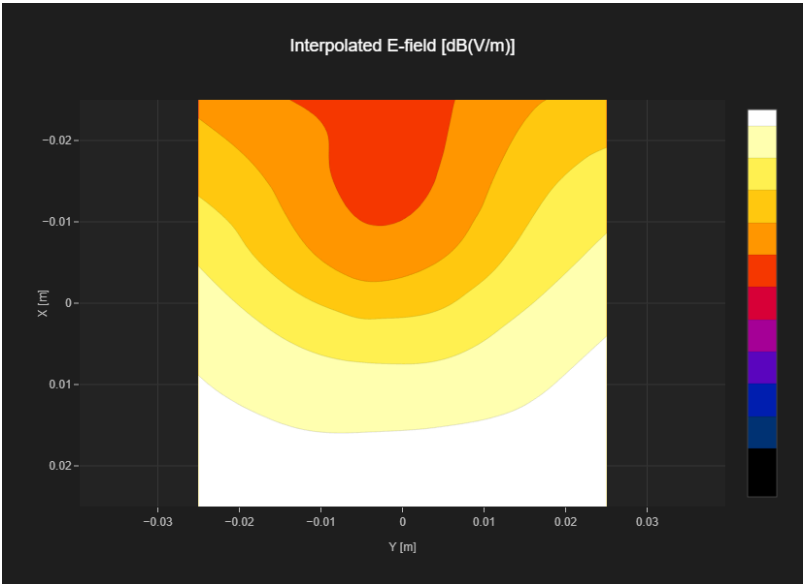
Band Name	Communication Systems Name	Channel	Frequency [MHz]
PCS 1900	GSM-FDD (TDMA, GMSK)	512	1850.2

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.45	20.44	3.63	24.07



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 14:44

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

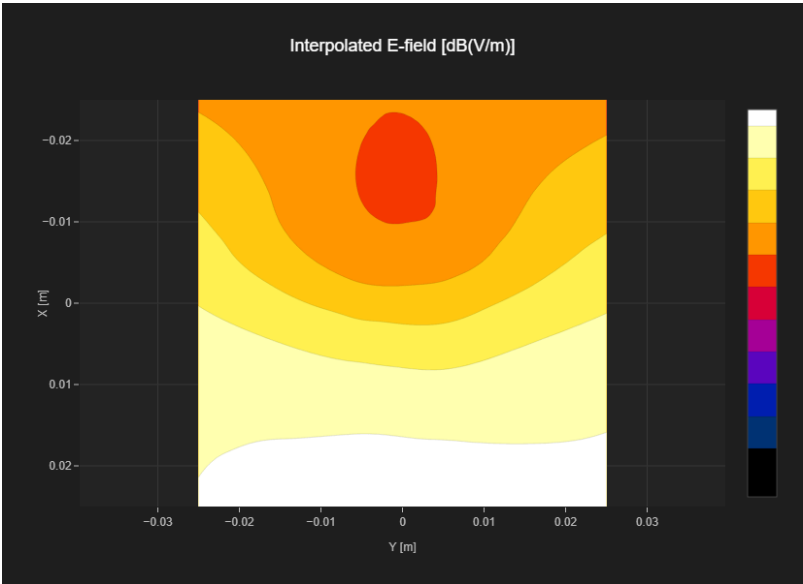
Band Name	Communication Systems Name	Channel	Frequency [MHz]
PCS 1900	GSM-FDD (TDMA, GMSK)	661	1880.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.6	20.17	3.63	23.8



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 15:04

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

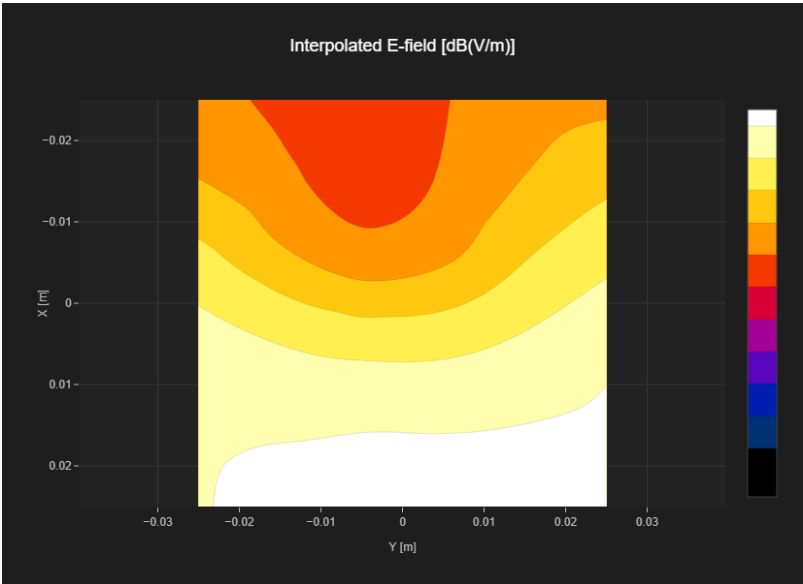
Band Name	Communication Systems Name	Channel	Frequency [MHz]
PCS 1900	GSM-FDD (TDMA, GMSK)	810	1909.8

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.27	19.91	3.63	23.54



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 15:18

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

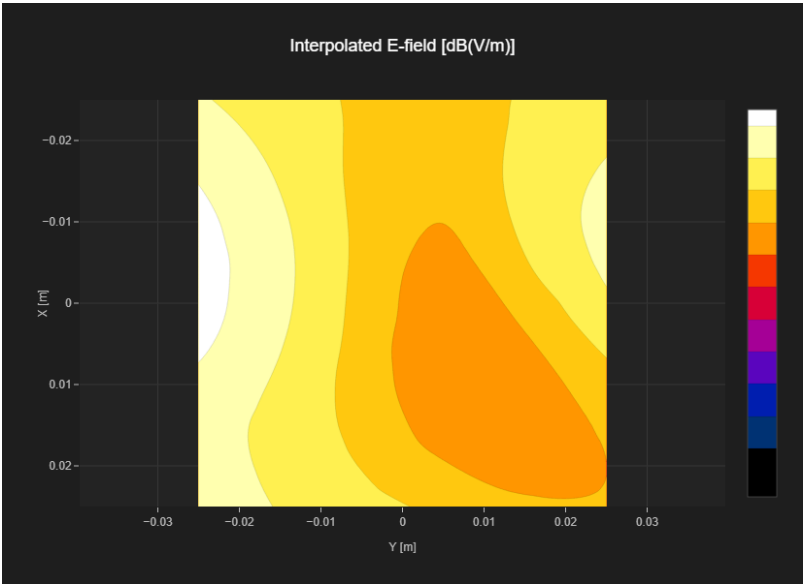
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	39750	2506.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
22.38	18.33	-1.44	16.89



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 15:23

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

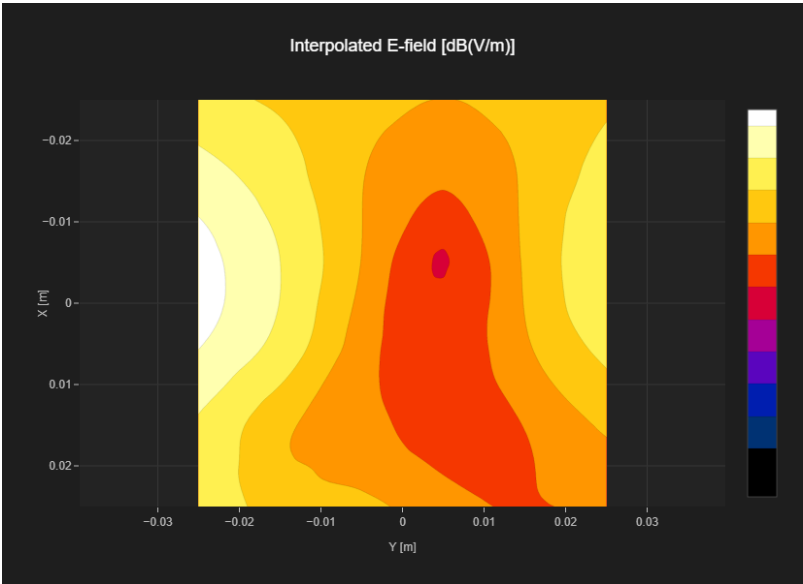
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	40620	2593.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

E _{max} [dB(V/m)]	E _{avg50x50 max} [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.21	17.91	-1.44	16.47



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 15:33

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

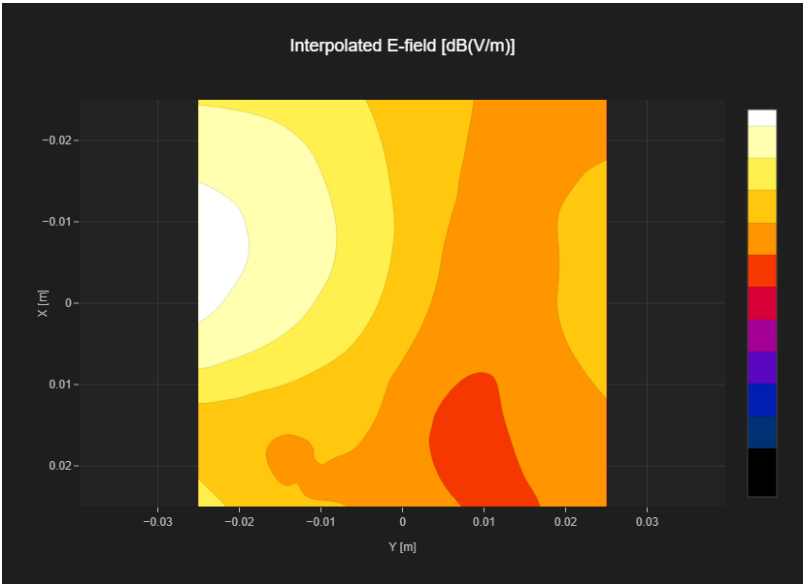
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	41490	2680.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
21.31	16.58	-1.44	15.14



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 15:48

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

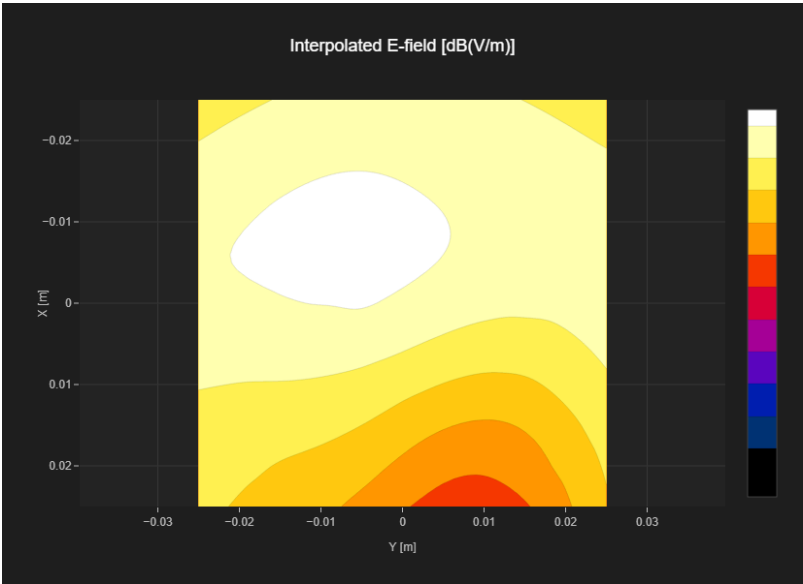
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	39750	2506.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
29.06	26.68	-1.44	25.24



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 15:43

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

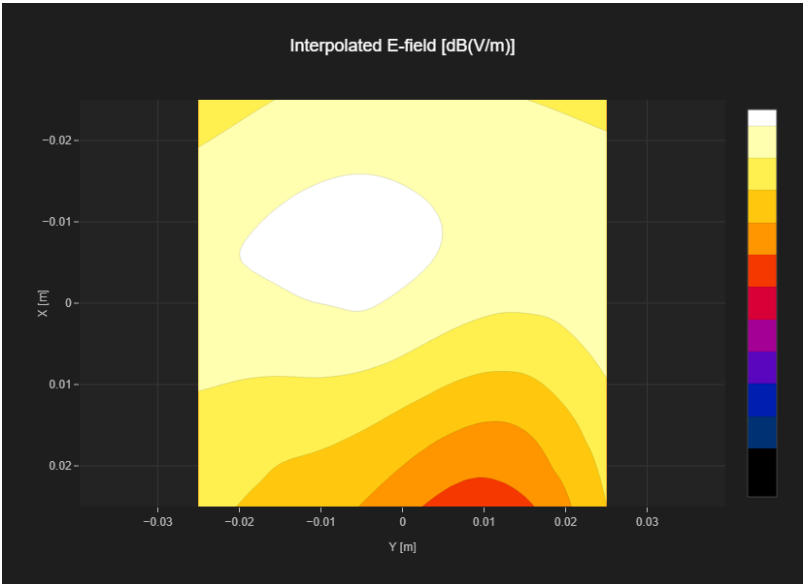
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	40620	2593.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
29.16	26.78	-1.44	25.34



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 15:39

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

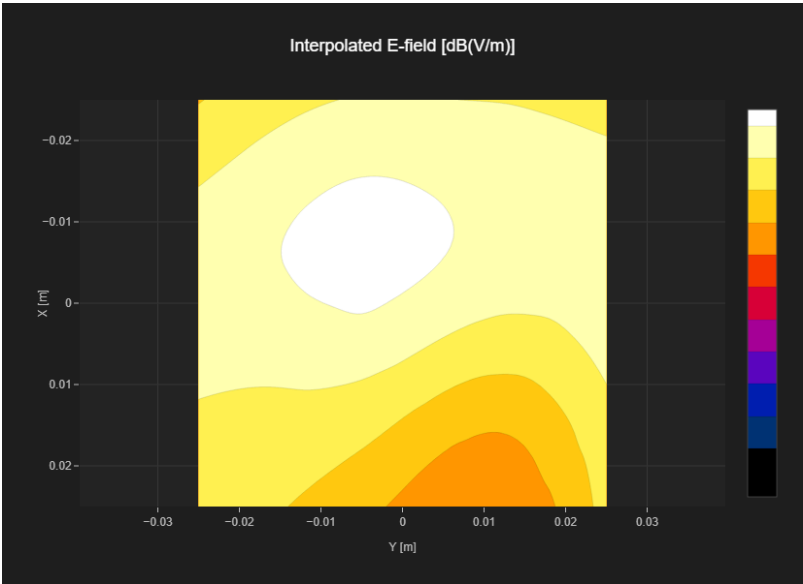
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	41490	2680.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
27.97	25.61	-1.44	24.17



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 16:35

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

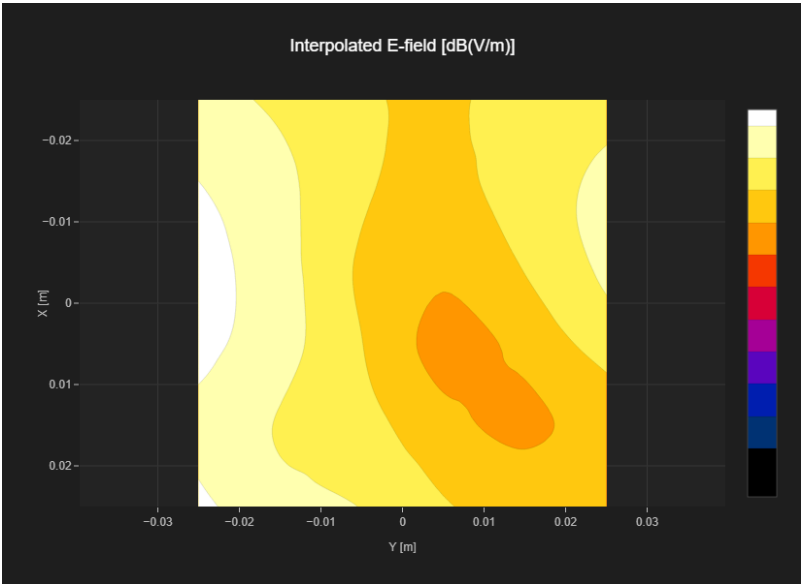
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	509202	2546.01

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
20.48	17.0	-1.64	15.36



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 16:40

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

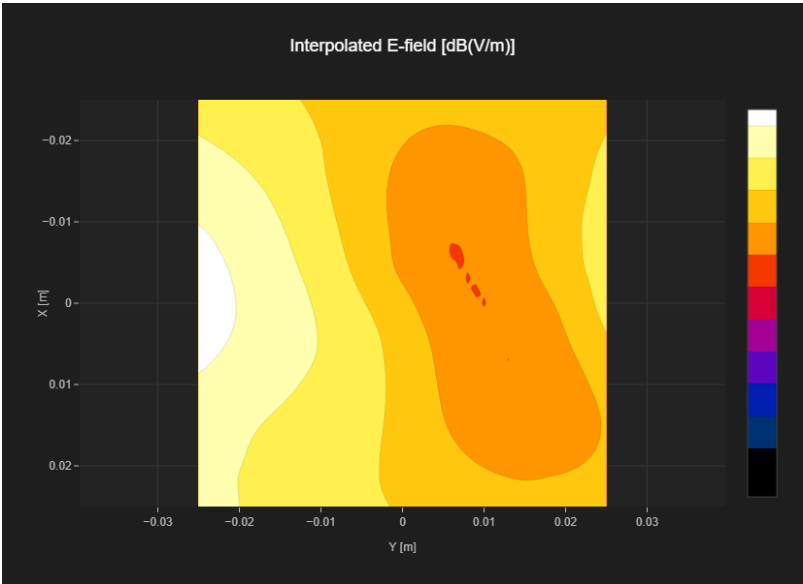
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	518598	2592.99

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
21.35	17.0	-1.64	15.36



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 16:43

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

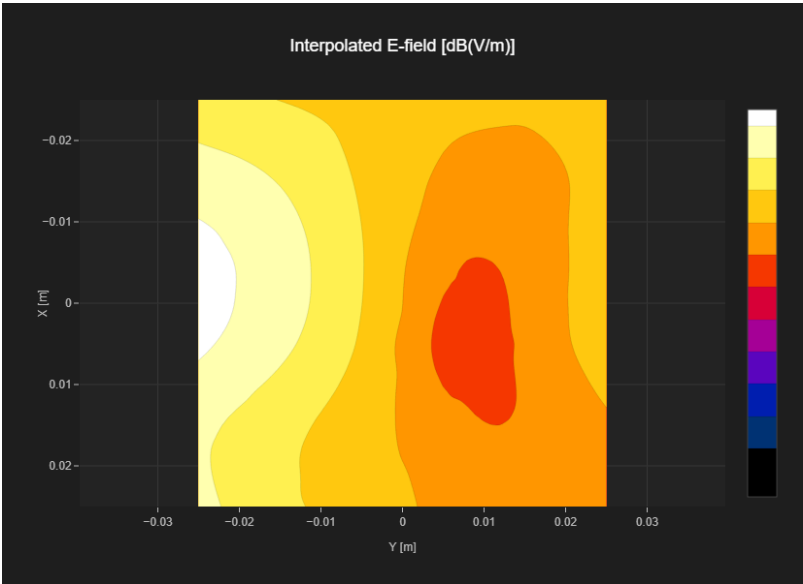
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	528000	2640.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
21.32	16.6	-1.64	14.96



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 16:11

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

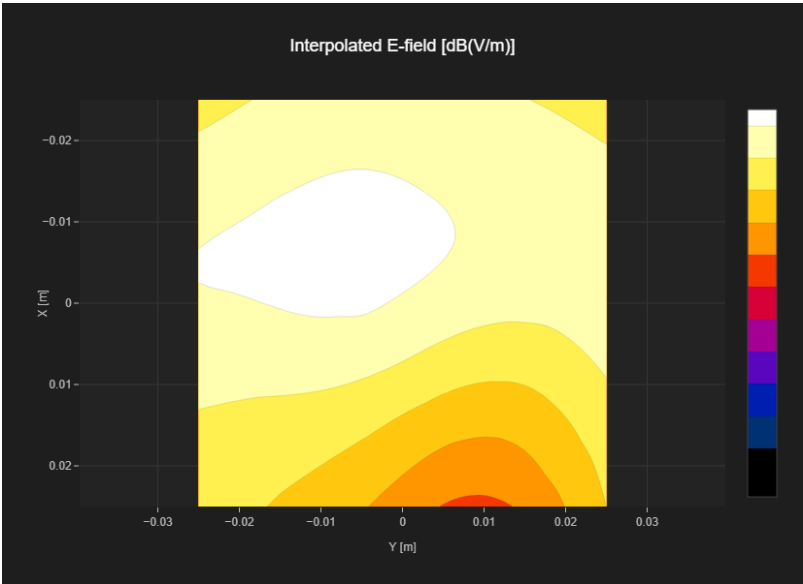
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	509202	2546.01

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
27.2	25.01	-1.64	23.37



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 16:19

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

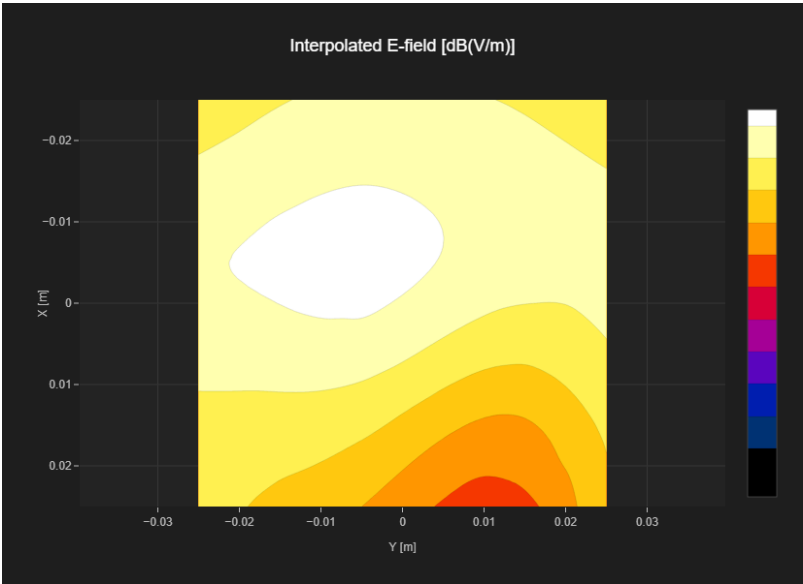
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	518598	2592.99

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
27.63	25.19	-1.64	23.55



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 16:23

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

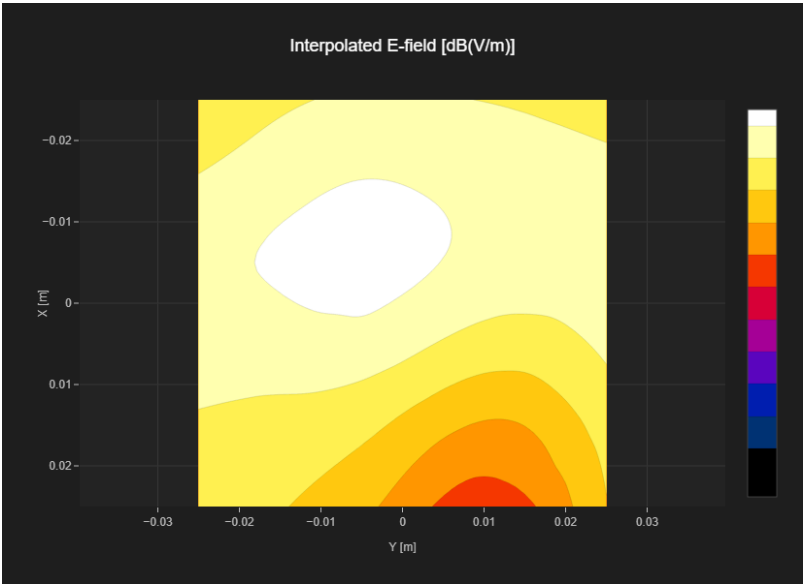
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	528000	2640.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
27.32	24.96	-1.64	23.32



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 16:53

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

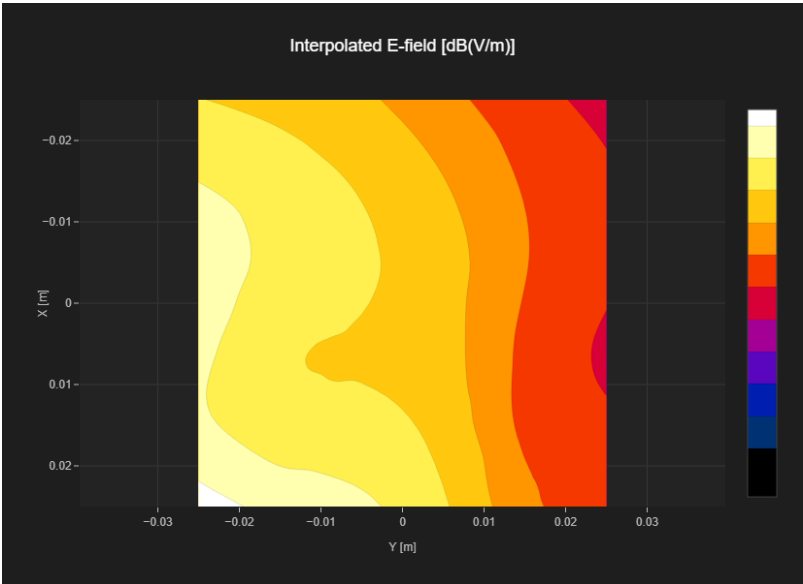
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n77	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	633334	3500.01

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
29.77	24.85	-1.64	23.21



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 16:58

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

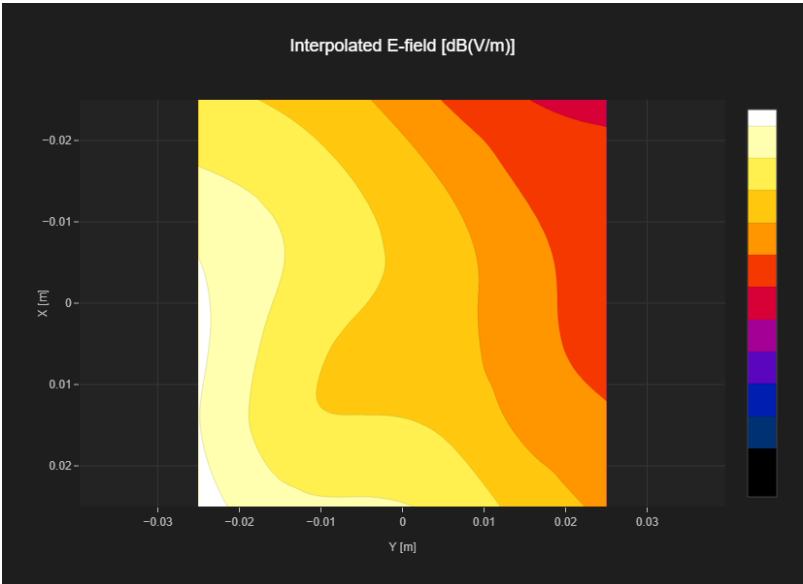
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n77	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	650000	3750.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
28.64	24.14	-1.64	22.5



RF Interference Potential Test Report

Measurement performed on December 19, 2024 at 17:02

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-A366U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4066	July 10, 2024	DAE4 Sn1468	August 15, 2024

Communication Systems

Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n77	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	662000	3930.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
28.97	24.09	-1.64	22.45

